FAIRCHILD
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PCN# : P218A
Issue Date : Oct. 17, 2012

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

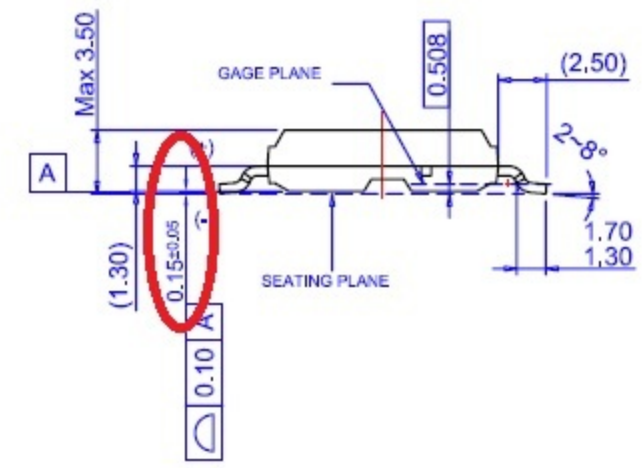
Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

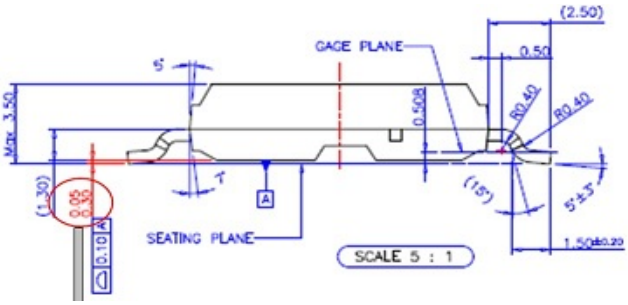
Expected First Shipment Date for Changed Product : Jan. 15, 2013

Expected First Date Code of Changed Product :1206

Description of Change (From) :
SPM5 SMD product Stand-off spec defined in published PKG outline drawing:
Which was 0.20 ~ 0.10mm (0.15+/-0.05mm).



Description of Change (To) :
SPM5 SMD product Stand-off spec defined which is 0.30~0.05mm(0.175+/-0.125mm).



Reason for Change:

SPEC correction.

To correct datasheet difference from Fairchild package of drawing(POD) by our mistake.

There is no any change to product because initial mass production followed this POD.

Affected Product(s):

FSB50250US	FSB50450S	FSB50450US
FSB50550US	FSB50825US	FSB52006S

Qualification Plan	Device	Package	Process	No. of Lots
Q20120339	FSB50825US	SPM5 SMD	N/A	1

Test Description:	Condition:	Standard :	Duration:	Results:
Full dimension inspection	Room temp.	SPM5D POD:FSSZ0437		0/30

Average value of raw standoff data(um)	184.74
Stdev of raw standoff data	19.15
Old standoff criteria LSL(um)	100
Old standoff criteria USL(um)	200
New standoff criteria LSL(um)	50
New standoff criteria USL(um)	300
CPK base on old standoff criteria	0.27
CPK base on new standoff criteria	2.01